## Notice of References Cited Application/Control No. 09/680,858 Examiner David H Kruse Applicant(s)/Patent Under Reexamination BEETHAM ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

	Designment Murches Dete						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification		
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## **NON-PATENT DOCUMENTS**

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	U	Swanson et al 1989, Theoretical and Applied Genetics 78:525-530.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.